



## Development and Applications of Microwave/Millimeter Wave Diagnostics in Industry, 2nd Edition

Guest Editors:

**Prof. Dr. Atsushi Mase**

Global Innovation Center, Kyushu University, Kasuga 816-8580, Japan

**Prof. Dr. Neville C. Luhmann**

1. Department of Electrical and Computer Engineering, University of California, Davis, CA 95616, USA  
2. Co-Director of Davis MM Wave Research Center, University of California, Davis, CA 95616, USA

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### Message from the Guest Editors

The ever accelerating progress in microwave- and millimeter-wave devices and circuits, such as monolithic microwave integrated circuits (MMICs), and data processing including computer technology has contributed to the rapid advancement in diagnostic technology. This includes micro- to millimeter-wave imaging including optics imaging, synthetic imaging, and MIMO (multi-input multi-output) imaging. They have become of critical importance in various applications due to the possibility of high localization and accessibility of the measurements.

In this Special Issue, the scientific papers related to industrial applications of micro- to millimeter-wave diagnostics will be accepted, which include system development, data processing techniques, system application results, and physics understandings of the results. The potential applications may include the above-mentioned measurements. However, many valuable studies can be accepted for future advancements in this field.





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## Editor-in-Chief

**Prof. Dr. Giulio Nicola Cerullo**

Dipartimento di Fisica,  
Politecnico di Milano, Piazza L.  
da Vinci 32, 20133 Milano, Italy

## Message from the Editor-in-Chief

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*Applied Sciences* Editorial Office  
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